

# FAST 74F166 Shift Register

## FAST Products

### FEATURES

- High impedance NPN base inputs for reduced loading (20 $\mu$ A in High and Low states)
- Synchronous parallel to serial applications
- Synchronous serial data input for easy expansion
- Clock enable for "do nothing" mode
- Asynchronous Master Reset
- Expandable to 16 bits in 8-bit increments

### DESCRIPTION

The 74F166 is a high speed 8-bit shift register that has fully synchronous serial parallel data entry selected by an active Low Parallel Enable ( $\overline{PE}$ ) input. When the  $\overline{PE}$  is Low one setup time before the Low-to-High clock transition, parallel data is entered into the register. When  $\overline{PE}$  is High, data is entered into internal bit position  $Q_0$  from serial data input ( $D_s$ ), and the remaining bits are shifted one place to the right ( $Q_0$ - $Q_1$ - $Q_2$ , etc.) with each positive going clock transition. For expansion of the register in parallel to serial converters, the  $Q_7$  output is connected to the  $D_s$  input of the succeeding

## 8-Bit Bidirectional Universal Shift Register Product Specification

TYPE	TYPICAL $f_{MAX}$	TYPICAL SUPPLY CURRENT (TOTAL)
74F166	175MHz	50mA

### ORDERING INFORMATION

PACKAGES	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$ ; $T_A = 0^\circ C$ to $+70^\circ C$
16-Pin Plastic DIP	N74F166N
16-Pin Plastic SO	N74F166D

### INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

PINS	DESCRIPTION	74F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
$D_0$ - $D_7$	Parallel data inputs	1.0/0.033	20 $\mu$ A/20 $\mu$ A
$D_s$	Serial data input (Shift Right)	2.0/0.066	40 $\mu$ A/40 $\mu$ A
CP	Clock input (Active rising edge)	1.0/0.033	20 $\mu$ A/20 $\mu$ A
$\overline{CE}$	Clock Enable input (Active Low)	1.0/0.033	20 $\mu$ A/20 $\mu$ A
$\overline{PE}$	Parallel Enable input (Active Low)	1.0/0.033	20 $\mu$ A/20 $\mu$ A
$\overline{MR}$	Master Reset input (Active Low)	2.0/0.066	40 $\mu$ A/40 $\mu$ A
$Q_7$	Data outputs	50/33	1.0mA/20mA

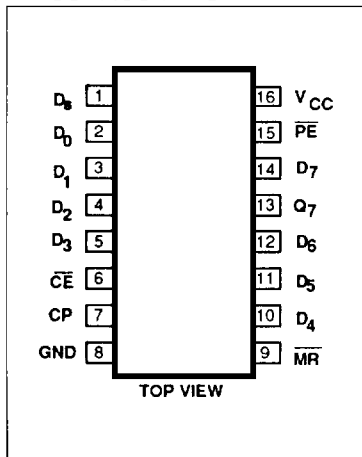
#### NOTE:

One (1.0) FAST Unit Load is defined as: 20 $\mu$ A in the High state and 0.6mA in the Low state.

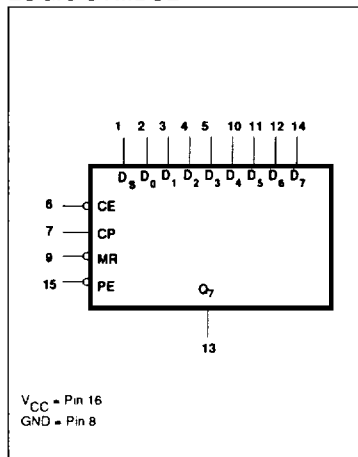
stage. The clock input is gated OR structure which allows one input to be used as an active-Low Clock Enable ( $\overline{CE}$ ) input. The pin assignment for the CP and  $\overline{CE}$  inputs is arbitrary and can be reversed for layout convenience. The Low-to-High

transition of  $\overline{CE}$  input should only take place while the CP is High for predictable operation. A Low on the Master Reset ( $\overline{MR}$ ) input overrides all other inputs and clears the register asynchronously, forcing all bit positions to a Low state.

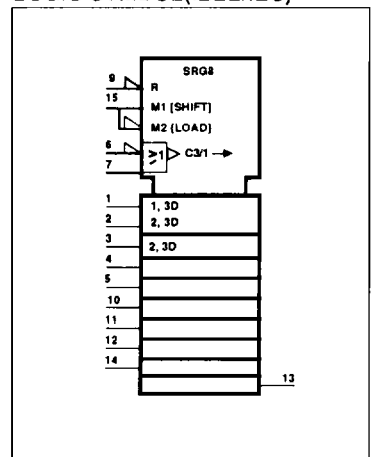
### PIN CONFIGURATION



### LOGIC SYMBOL



### LOGIC SYMBOL (IEEE/IEC)



# Shift Register

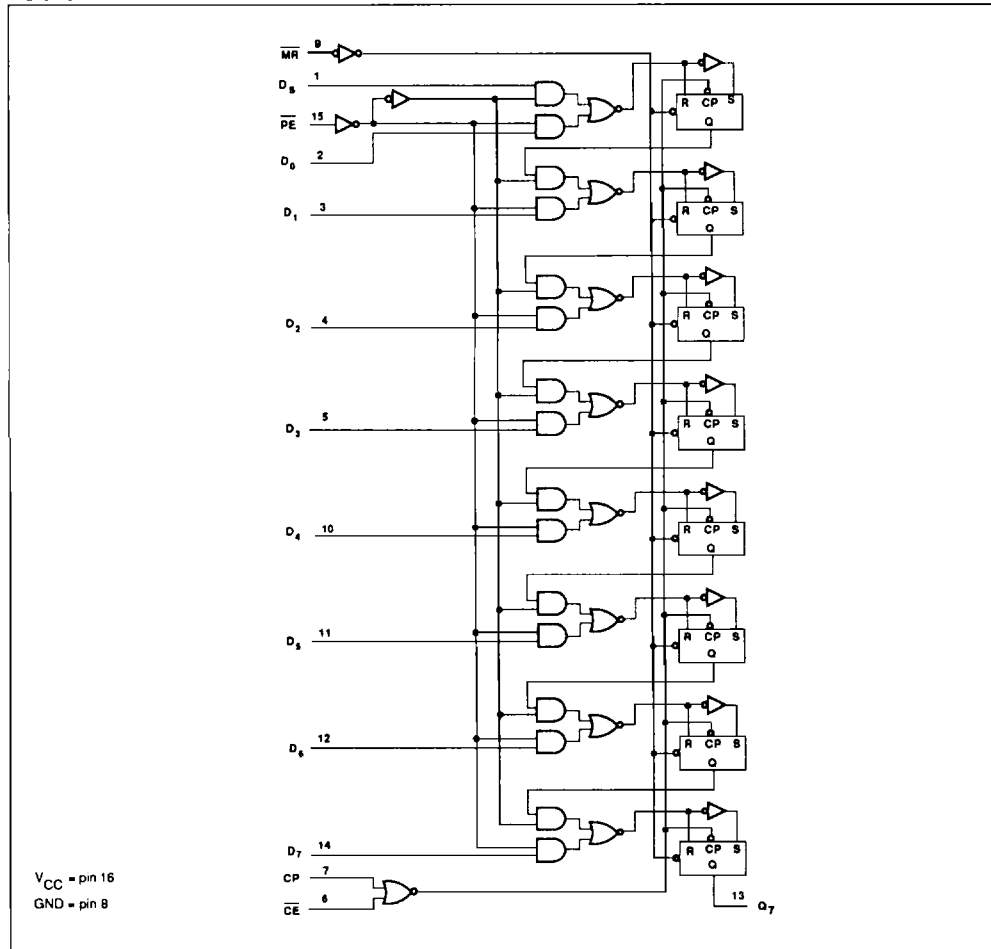
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## FUNCTION TABLE

INPUTS					Q <sub>n</sub> REGISTER		OUTPUT	OPERATING MODE
PE	CE	CP	D <sub>s</sub>	D <sub>0</sub> - D <sub>7</sub>	Q <sub>0</sub>	Q <sub>1</sub> - Q <sub>6</sub>	Q <sub>7</sub>	
l	l	↑	X	l-l	L	L-L	L	Parallel load
l	l	↑	X	h-h	H	H-H	H	
h	l	↑	l	X-X	L	q <sub>0</sub> - q <sub>5</sub>	q <sub>6</sub>	Serial shift
h	l	↑	h	X-X	H	q <sub>0</sub> - q <sub>5</sub>	q <sub>6</sub>	
X	h	X	X	X-X	q <sub>0</sub>	q <sub>1</sub> - q <sub>6</sub>	q <sub>7</sub>	Hold (do nothing)

- H = High voltage level
- h = High voltage level one set-up time prior to the Low-to-High clock transition
- L = Low voltage level
- l = Low voltage level one set-up time prior to the Low-to-High clock transition
- q<sub>n</sub> = Lower case letters indicate the state of the referenced input (or output) one set-up time prior to the Low-to-High clock transition
- X = Don't care
- ↑ = Low-to-High clock transition

## LOGIC DIAGRAM



# Shift Register

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## ABSOLUTE MAXIMUM RATINGS (Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
$V_{CC}$	Supply voltage	-0.5 to +7.0	V
$V_{IN}$	Input voltage	-0.5 to +7.0	V
$I_{IN}$	Input current	-30 to +5	mA
$V_{OUT}$	Voltage applied to output in High output state	-0.5 to $V_{CC}$	V
$I_{OUT}$	Current applied to output in Low output state	40	mA
$T_A$	Operating free-air temperature range	0 to +70	°C
$T_{STG}$	Storage temperature	-65 to +150	°C

## RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		Min	Nom	Max	
$V_{CC}$	Supply voltage	4.5	5.0	5.5	V
$V_{IH}$	High-level input voltage	2.0			V
$V_{IL}$	Low-level input voltage			0.8	V
$I_{IK}$	Input clamp current			-18	mA
$I_{OH}$	High-level output current			-1	mA
$I_{OL}$	Low-level output current			20	mA
$T_A$	Operating free-air temperature range	0		70	°C

## DC ELECTRICAL CHARACTERISTICS (Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS <sup>1</sup>	LIMITS			UNIT	
			Min	Typ <sup>2</sup>	Max		
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN}, V_{IL} = \text{MAX}$	$\pm 10\%V_{CC}$	2.5		V	
		$V_{IH} = \text{MIN}, I_{OH} = \text{MAX}$	$\pm 5\%V_{CC}$	2.7	3.4	V	
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN}, V_{IL} = \text{MAX}$	$\pm 10\%V_{CC}$		0.30	0.50	V
		$V_{IH} = \text{MIN}, I_{OL} = \text{MAX}$	$\pm 5\%V_{CC}$		0.30	0.50	V
$V_{IK}$	Input clamp voltage	$V_{CC} = \text{MIN}, I_I = I_{IK}$		-0.73	-1.2	V	
$I_I$	Input current at maximum input voltage	others $\overline{CE}, CP^3$ $V_{CC} = 0.0V, V_I = 7.0V$				100	$\mu A$
			$I_{IH}$	High-level input current	others $\overline{MR}, D_s$ $V_{CC} = \text{MAX}, V_I = 2.7V$		20
		40				$\mu A$	
$I_{IL}$	Low-level input current	others $\overline{MR}, D_s$ $V_{CC} = \text{MAX}, V_I = 0.5V$				-20	$\mu A$
						-40	$\mu A$
$I_{OS}$	Short circuit output current <sup>4</sup>	$V_{CC} = \text{MAX}$		-60		-150	mA
$I_{CC}$	Supply current (total)	$V_{CC} = \text{MAX}, \overline{PE} = \overline{CE} = D_n = \text{GND}, \overline{MR} = D_s = 4.5V, CP = \uparrow$		50	70		mA

**NOTES:**

- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- All typical values are at  $V_{CC} = 5V, T_A = 25^\circ C$ .
- When testing CP,  $\overline{CE}$  must remain in High state, whereas CP must remain in High state when testing  $\overline{CE}$ .
- Not more than one output should be shorted at a time. For testing  $I_{OS}$ , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter test,  $I_{OS}$  tests should be performed last.

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## AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			T <sub>A</sub> = +25°C V <sub>CC</sub> = 5V C <sub>L</sub> = 50pF R <sub>L</sub> = 500Ω			T <sub>A</sub> = 0°C to +70°C V <sub>CC</sub> = 5V ±10% C <sub>L</sub> = 50pF R <sub>L</sub> = 500Ω		
			Min	Typ	Max	Min	Max	
f <sub>MAX</sub>	Maximum clock frequency	Waveform 1	135	175		110		MHz
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation delay CP to Q <sub>7</sub>	Waveform 1	5.0 4.0	7.5 6.0	10.0 8.0	5.0 3.5	12.0 9.0	ns
t <sub>PHL</sub>	Propagation delay MR to Q <sub>7</sub>	Waveform 2	4.0	6.5	8.5	4.0	9.5	ns

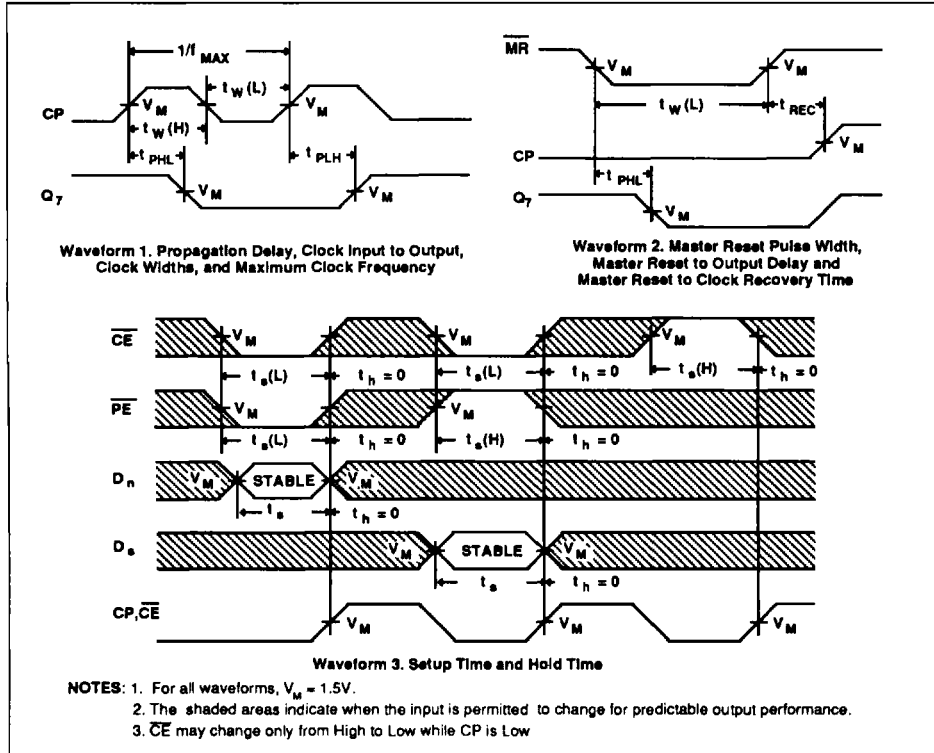
## AC SETUP REQUIREMENTS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			T <sub>A</sub> = +25°C V <sub>CC</sub> = 5V C <sub>L</sub> = 50pF R <sub>L</sub> = 500Ω			T <sub>A</sub> = 0°C to +70°C V <sub>CC</sub> = 5V ±10% C <sub>L</sub> = 50pF R <sub>L</sub> = 500Ω		
			Min	Typ	Max	Min	Max	
t <sub>s</sub> (H) t <sub>s</sub> (L)	Setup time, High or Low D <sub>n</sub> , D <sub>s</sub> to CP, CE	Waveform 3	3.0 2.5			4.0 3.0		ns
t <sub>h</sub> (H) t <sub>h</sub> (L)	Hold time, High or Low D <sub>n</sub> , D <sub>s</sub> to CP	Waveform 3	0 0			1.0 0		ns
t <sub>h</sub> (H) t <sub>h</sub> (L)	Hold time, High or Low D <sub>n</sub> , D <sub>s</sub> to CE	Waveform 3	1.5 0			2.0 0		ns
t <sub>s</sub> (L)	Setup time, Low CE to CP	Waveform 3	5.0			6.0		ns
t <sub>h</sub> (H)	Hold time, High CE to CP	Waveform 3	0			0		ns
t <sub>s</sub> (H) t <sub>s</sub> (L)	Setup time, High or Low PE to CP, CE	Waveform 3	3.0 3.0			4.0 4.0		ns
t <sub>h</sub> (H) t <sub>h</sub> (L)	Hold time, High or Low PE to CP, CE	Waveform 3	0 0			0 0		ns
t <sub>w</sub> (H) t <sub>w</sub> (L)	CP Pulse width, High or Low	Waveform 1	3.0 4.5			3.5 5.0		ns
t <sub>w</sub> (L)	MR Pulse width, Low	Waveform 2	4.0			4.0		ns
t <sub>REC</sub>	Recovery time MR to CP	Waveform 2	4.0			4.5		ns

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## AC WAVEFORMS



## TEST CIRCUIT AND WAVEFORMS

